At-Speed Test and Diagnosis of Small Delay Defects
in Advanced Nanometer Technologies

1. **Simulation of Small Delay Defects (Eric Schneider)**


2. **Test Pattern Generation Methods for Small Delay Defects (Atefe Dalirsani)**


3. **Robust and Hazard-Free Test Generation for Small Delay Defects (Atefe Dalirsani)**


4. **Nearly Robust Test Generation (Atefe Dalirsani)**


5. **Modeling of Delay Faults (Atefe Dalirsani)**


6. **Deterministic Diagnosis of Small Delay Defects (Eric Schneider)**


7. **Small Delay Defect Diagnosis based on Statistical Timing Analysis (Eric Schneider)**


8. **Faster-Than At-Speed Test (Chang Liu)**


9. **On-Chip Delay Measurement (Chang Liu)**


10. **On-Chip Clock Generation (Chang Liu)**


11. **Shift-Power Reduction in BIST (Chang Liu)**


12. **Power-Noise/IR-Drop Reduction (Eric Schneider)**